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| <b>INFORMATION DISCLOSURE<br/>STATEMENT BY APPLICANT</b><br><br><i>(Use as many sheets as necessary)</i> |  | Application Number     | 10/644,745      |
|  |  | Filing Date            | August 21, 2003 |
|  |  | First Named Inventor   | Hideki TANAKA   |
|  |  | Art Unit               | 2878            |
|  |  | Examiner Name          | J. Lee          |
|  |  | Attorney Docket Number | 07553.0044-00   |

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| Sheet | 1 | of | 1 |
|-------|---|----|---|

| U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS |                       |   |   |   |   |
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| FOREIGN PATENT DOCUMENTS |                       |  |                                |   |   |                          |
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| Examiner Initials        | Cite No. <sup>1</sup> | Foreign Patent Document<br>Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known) | Publication Date<br>MM-DD-YYYY | Name of Patentee or Applicant of Cited Document | Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear | Translation <sup>6</sup> |
| JL                       | 1                     | JP 64-081197   | 03-27-1989                     | Hitachi Ltd                                     |   | Abstract                 |
| JL                       | 2                     | JP 2000-100795   | 04-07-2000                     | Seiko Epson Corp.                               |   | Abstract                 |
| JL                       | 3                     | JP 2001-319922   | 11-16-2001                     | NEC Corp.                                       |   | Abstract                 |
| JL                       | 4                     | WO 00/03421  | 01-20-2000                     | Applied Materials Inc.                          |   | n/a                      |

| NON PATENT LITERATURE DOCUMENTS |                       |   |                          |
|---------------------------------|-----------------------|---|--------------------------|
| Examiner Initials               | Cite No. <sup>1</sup> | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. | Translation <sup>6</sup> |
| JL                              | 5                     | English Abstract of JP 64-081197  |                          |
| JL                              | 6                     | English Abstract of JP 2000-100795  |                          |
| JL                              | 7                     | English Abstract of JP 2001-319922  |                          |
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| Examiner Signature | /John Lee/ (01/05/2007) | Date Considered |  |
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